

Advanced Electron Microscopy: Novel Perspectives for Soft Matter Sciences

Because of recent enormous progress in the field of electron microscopy, we believe it is the right time to introduce the novel advanced tools and methods to you, and to demonstrate valuable applications in the field of soft matter research.

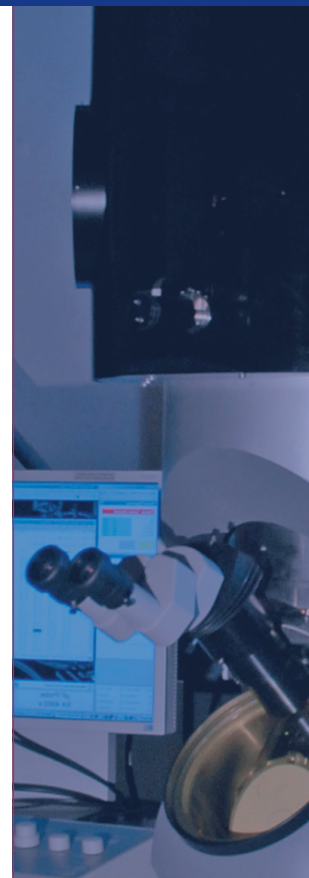
The technical focus of the Symposium is Electron Tomography, which allows for 3D volume reconstruction of the organisation of matter, EELS (electron energy loss spectroscopy) for chemical recognition and determination e.g. of electronic structures, Scanning TEM (STEM) and Dual Beam Microscopy (combination of Scanning Electron Microscope and Focused Ion Beam) both as techniques rarely applied in soft matter research.

As one highlight we like to introduce to a broad community new methodologies that allow for morphology analysis of purely carbon-based materials, without staining, and for volume characterisation of several micrometer thick specimens with nanometer resolution.

Date	: Monday 8 September 2008
Time	: 9.30 – 17.00, including buffet lunch
Venue	: Eindhoven University of Technology (TU/e), Chemical Engineering and Chemistry, The Netherlands
Registration	: www.polymers.nl
Organizers	: Dr. Joachim Loos, Chemical Engineering and Chemistry, TU/e and Dutch Polymer Institute; in cooperation with FEI Company.

Speakers

Dr. Christian Kübel	Head of the Electron Microscopy Group, Fraunhofer Institute for Manufacturing Technology and Applied Materials Research (IFAM)
Dr. Hiroshi Jinnai	Associate Professor, Department of Macromolecular Science and Engineering, Graduate School of Science and Engineering, Kyoto Institute of Technology
Prof. dr. Ferdinand Hofer	Head of the Institute, Austrian Centre for Electron Microscopy and Nanoanalysis, Institute for Electron Microscopy of the TU Graz, Graz Centre for Electron Microscopy
Dr. Erwan Sourty	TEM Applications Engineer, Shanghai Nanoport, FEI Company



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